

JOURNAL OF ELECTRONIC TESTING:
Theory and Applications
(JETTA)

JOURNAL OF
**ELECTRONIC
TESTING**
Theory and Applications (JETTA)

Editor in Chief: Vishwani Agrawal

Volume 38, Number 5, October 2022

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JOURNAL OF ELECTRONIC TESTING

Volume 38, Number 5, October 2022 463–574

A journal serving electronic test professionals
in concurrence with the Test Technology Technical Council
(TTTC) of the IEEE Computer Society



Springer



ISSN: 0923-8174